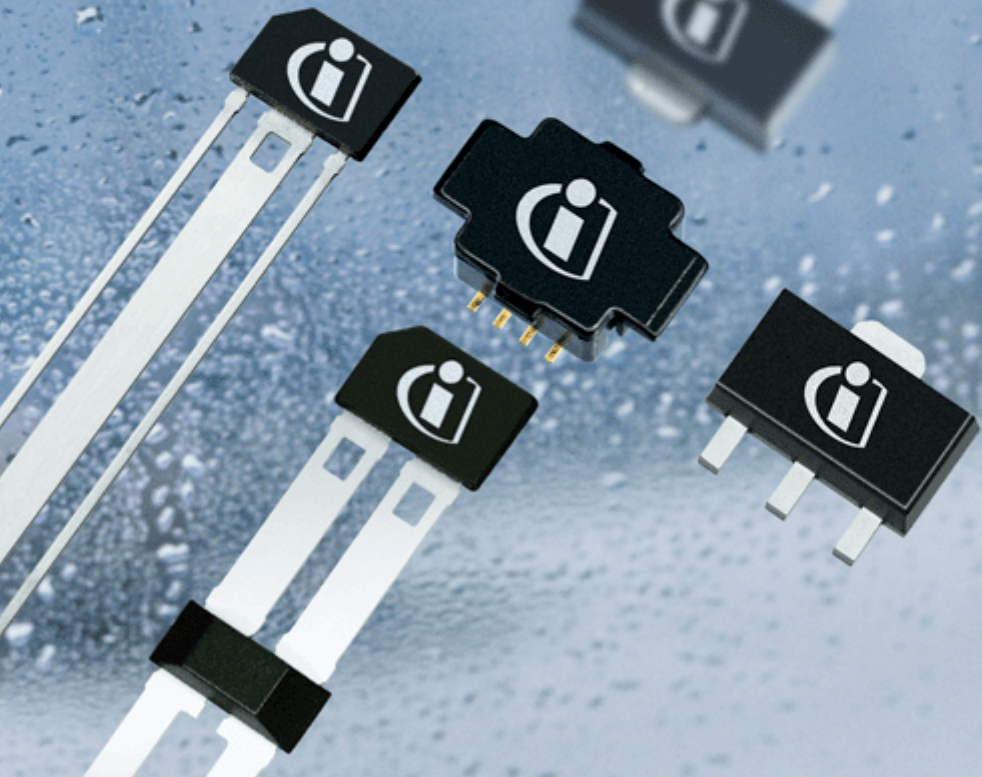


TLE4946H TLE4946-1L

High Precision Bipolar Hall-Effect Latch



Sensors



Never stop thinking

Edition 2005-10

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TLE4946H

TLE4946-1L

Revision History: 2005-10

V 1.1

Previous Version: 1.0

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14	Figure 6 Correction of dimensions
16	Figure 10 Correction of dimensions
11	Table 7 New entry: Magnetic Offset for TLE4946-1L

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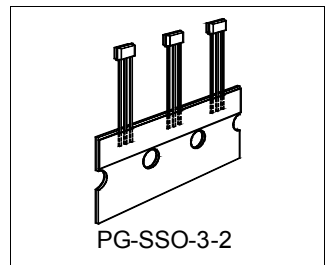
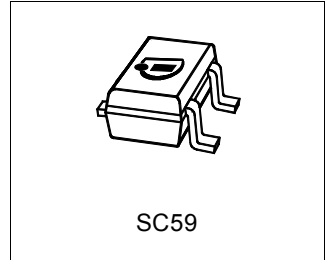


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1 Overview

1.1 Features

- 2.7 V to 24 V supply voltage operation
- Operation from unregulated power supply
- High sensitivity and high stability of the magnetic switching points
- High resistance to mechanical stress by Active Error Compensation
- Reverse battery protection (– 18 V)
- Superior temperature stability
- Peak temperatures up to 195°C without damage
- Low jitter (typ. 1 μ s)
- High ESD performance (\pm 6 kV HBM)
- Digital output signal
- SMD package SC59 (SOT23 compatible) - (TLE4946H)
- Leaded package PG-SSO-3-2 - (TLE4946-1L)



1.2 Functional Description

The TLE4946H and the TLE4946-1L are integrated circuit Hall-effect sensors designed specifically for highly accurate applications.

Precise magnetic switching points and high temperature stability are achieved by active compensation circuits and chopper techniques on chip.

Type	Package
TLE4946H	SC59
TLE4946-1L	PG-SSO-3-2

1.3 Pin Configuration (top view)

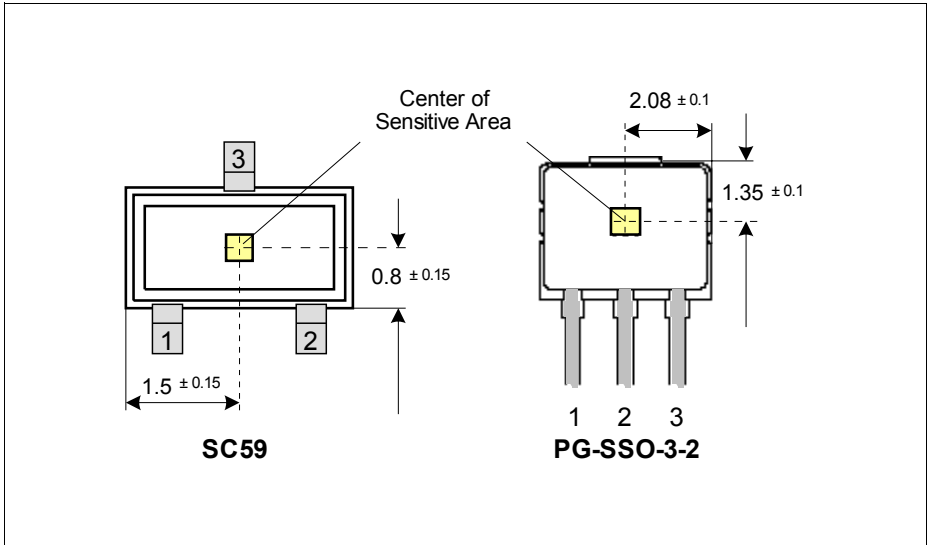


Figure 1 Pin Definition and Center of Sensitive Area

Table 1 Pin Definitions and Functions SC59

Pin No.	Symbol	Function
1	V_S	Supply voltage
2	Q	Output
3	GND	Ground

Table 2 Pin Definitions and Functions PG-SSO-3-2

Pin No.	Symbol	Function
1	V_S	Supply voltage
2	GND	Ground
3	Q	Output

2 General

2.1 Block Diagram

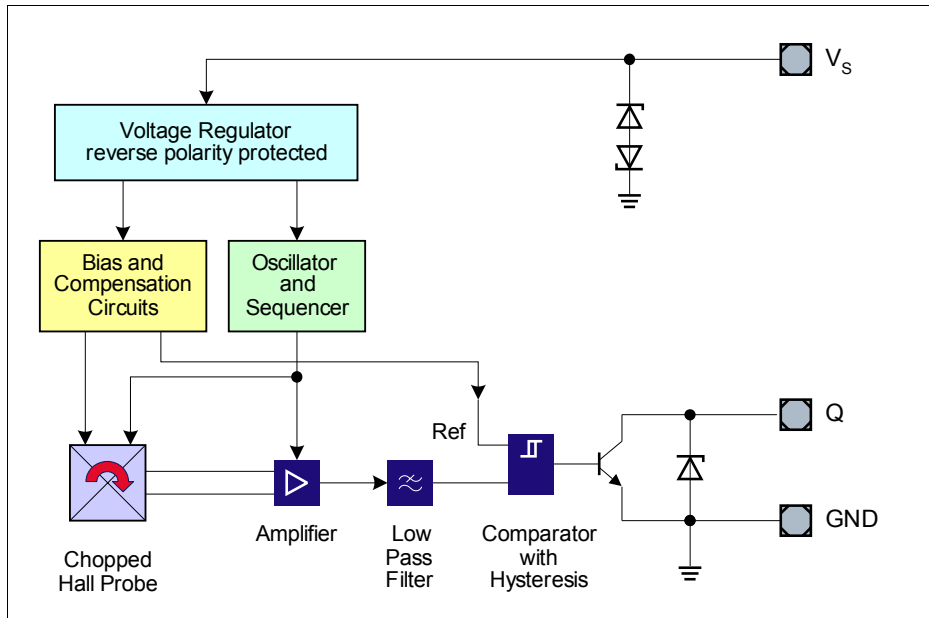


Figure 2 Block Diagram

2.2 Circuit Description

The chopped Hall IC Switch comprises a Hall probe, bias generator, compensation circuits, oscillator, and output transistor.

The bias generator provides currents for the Hall probe and the active circuits. Compensation circuits stabilize the temperature behavior and reduce technology variations.

The Active Error Compensation rejects offsets in signal stages and the influence of mechanical stress to the Hall probe caused by molding and soldering processes and other thermal stresses in the package.

This chopper technique together with the threshold generator and the comparator ensure high accurate magnetic switching points.

3 Maximum Ratings

Table 3 Absolute Maximum Ratings
 $T_j = -40^{\circ}\text{C to } 150^{\circ}\text{C}$

Parameter	Symbol	Limit Values		Unit	Conditions
		min.	max.		
Supply voltage	V_S	- 18 - 18 - 18	18 24 26	V	for 1 h, $R_s \geq 200 \Omega$ for 5 min, $R_s \geq 200 \Omega$
Supply current through protection device	I_S	- 50	+ 50	mA	
Output voltage	V_Q	- 0.7 - 0.7	18 26	V	for 5 min @ 1.2 k Ω pull up
Continuous output current	I_Q	- 50	+ 50	mA	
Junction temperature	T_j	- - - -	155 165 175 195	$^{\circ}\text{C}$	for 2000 h (not additive) for 1000 h (not additive) for 168 h (not additive) for 3 x 1 h (additive)
Storage temperature	T_S	- 40	150	$^{\circ}\text{C}$	
Magnetic flux density	B	-	unlimited	mT	

Note: Stresses above those listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 4 ESD Protection ¹⁾

Parameter	Symbol	Limit Values		Unit	Notes
		min.	max.		
ESD voltage	V_{ESD}	-	± 6	kV	HBM, $R = 1.5 \text{ k}\Omega$, $C = 100 \text{ pF}$ $T_A = 25^{\circ}\text{C}$

1) Human Body Model (HBM) tests according to: EOS/ESD Association Standard S5.1-1993 and Mil. Std. 883D method 3015.7

4 Operating Range

Table 5 Operating Range

Parameter	Symbol	Limit Values			Unit	Conditions
		min.	typ.	max.		
Supply voltage	V_S	2.7	–	18	V	
Output voltage	V_Q	– 0.7	–	18	V	
Junction temperature	T_j	– 40	–	150	°C	
Output current	I_Q	0	–	20	mA	

5 Electrical and Magnetic Parameters

Table 6 Electrical Characteristics ¹⁾.

Parameter	Symbol	Limit Values			Unit	Conditions
		min.	typ.	max.		
Supply current	I_S	2	4	6	mA	$V_S = 2.7 \text{ V} \dots 18 \text{ V}$
Reverse current	I_{SR}	0	0.2	1	mA	$V_S = -18 \text{ V}$
Output saturation voltage	V_{QSAT}	–	0.3	0.6	V	$I_Q = 20 \text{ mA}$
Output leakage current	I_{QLEAK}	–	0.05	10	μA	for $V_Q = 18 \text{ V}$
Output fall time	t_f	–	0.02	1	μs	$R_L = 1.2 \text{ k}\Omega$; $C_L = 50 \text{ pF}$ see: Figure 3 “Timing Definition” on Page 12
Output rise time	t_r	–	0.4	1	μs	
Chopper frequency	f_{OSC}	–	320	–	kHz	
Switching frequency	f_{SW}	0	–	15 ²⁾	kHz	
Delay time ³⁾	t_d	–	13	–	μs	
Output jitter ⁴⁾	t_{QJ}	–	1	–	μs_{RMS}	Typical value for square wave signal 1 kHz
Power-on time ⁵⁾	t_{PON}	–	13	–	μs	$V_S \geq 2.7 \text{ V}$
Thermal resistance ⁶⁾	R_{thJA}	–	100	–	K/W	SC59
		–	–	190		PG-SSO-3-2

1) over operating range, unless otherwise specified. Typical values correspond to $V_S = 12 \text{ V}$ and $T_A = 25^\circ\text{C}$

2) To operate the sensor at the max. switching frequency, the value of the magnetic signal amplitude must be 1.4 times higher than for static fields.

This is due to the - 3 dB corner frequency of the low pass filter in the signal path.

3) Systematic delay between magnetic threshold reached and output switching

4) Jitter is the unpredictable deviation of the output switching delay

5) Time from applying $V_S \geq 2.7 \text{ V}$ to the sensor until the output state is valid

6) Thermal resistance from junction to ambient

Calculation of the ambient temperature (SC59 example)

e.g. for $V_S = 12.0 \text{ V}$, $I_{Styp} = 4 \text{ mA}$, $V_{QSATtyp} = 0.3 \text{ V}$ and $I_Q = 20 \text{ mA}$:

Power Dissipation: $P_{DIS} = 54.0 \text{ mW}$.

In $T_A = T_j - (R_{thJA} \times P_{DIS}) = 175^\circ\text{C} - (100 \text{ K/W} \times 0.054 \text{ W})$

Resulting max. ambient temperature: $T_A = 169.6^\circ\text{C}$

Electrical and Magnetic Parameters
Table 7 Magnetic Characteristics TLE4946H¹⁾

Parameter	Symbol	T_j [°C]	Limit Values			Unit	Notes
			min.	typ.	max.		
Operate point	B_{OP}	- 40	11.8	15.8	19.2	mT	TLE4946H
		25	11.0	14.0	17.0		TLE4946-1L
		150	6.1	9.6	13.7		
		- 40	11.3	15.4	19.5		
		25	11.0	15.0	19.0		
		150	10.5	14.3	18.1		
Release point	B_{RP}	- 40	- 19.2	- 15.8	- 11.8	mT	TLE4946H
		25	- 17.0	- 14.0	- 11.0		TLE4946-1L
		150	- 13.7	- 9.6	- 6.1		
		- 40	- 19.5	- 15.4	- 11.3		
		25	- 19.0	- 15.0	- 11.0		
		150	- 18.1	- 14.3	- 10.5		
Hysteresis	B_{HYS}	- 40	-	-	-	mT	TLE4946H
		25	22.0	28.0	34.0		TLE4946-1L
		150	-	-	-		
		- 40	-	-	-		
		25	22.0	30.0	38.0		
		150	-	-	-		
Magnetic Offset	B_{OFF}	- 40	-	-	-	mT	TLE4946H
		25	- 3.0	-	3.0		TLE4946-1L
		150	-	-	-		
		- 40	-	-	-		
		25	- 2.0	-	2.0		
		150	-	-	-		
Temperature compensation of magn. thresholds	TC	-	-	- 2000	-	ppm/°C	TLE4946H
		-	-	- 350	-		TLE4946-1L
Repeatability of magnetic thresholds ³⁾	B_{REP}		-	20	-	μT_{RMS}	Typ. value for $\Delta B / \Delta t$ > 12 mT/ms

1) over operating range, unless otherwise specified. Typical values correspond to $V_S = 12$ V.

2) $B_{OFF} = (B_{OP} + B_{RP}) / 2$

3) B_{REP} is equivalent to the noise constant

Note: Typical characteristics specify mean values expected over the production spread.

Field Direction Definition

Positive magnetic fields related with south pole of magnet to the branded side of package.

6 Timing Diagram

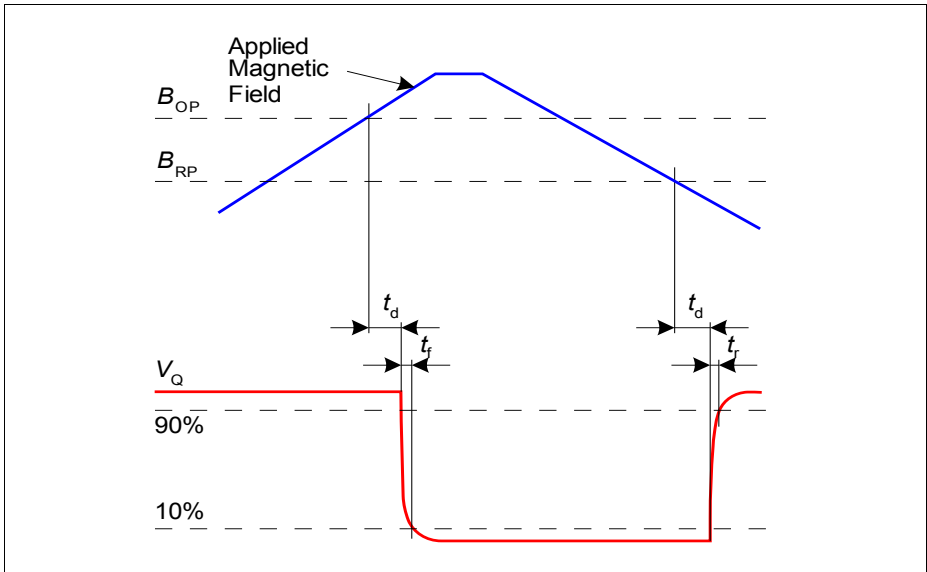


Figure 3 Timing Definition

7 Package Information

7.1 Package Marking

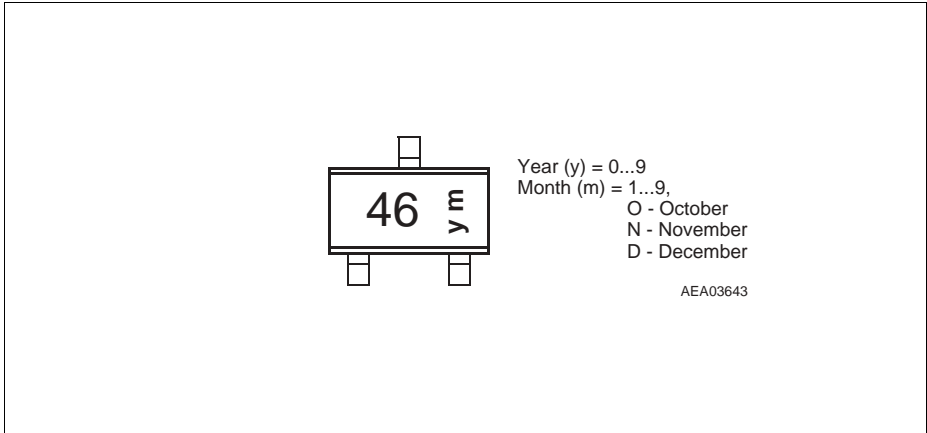


Figure 4 Marking TLE4946H

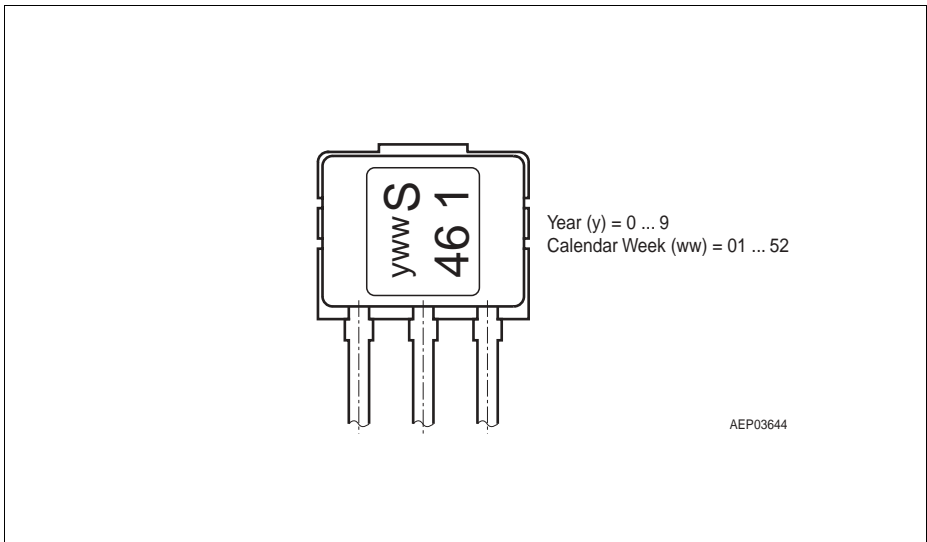


Figure 5 Marking TLE4946-1L

7.2 Distance between Chip and Package Surface

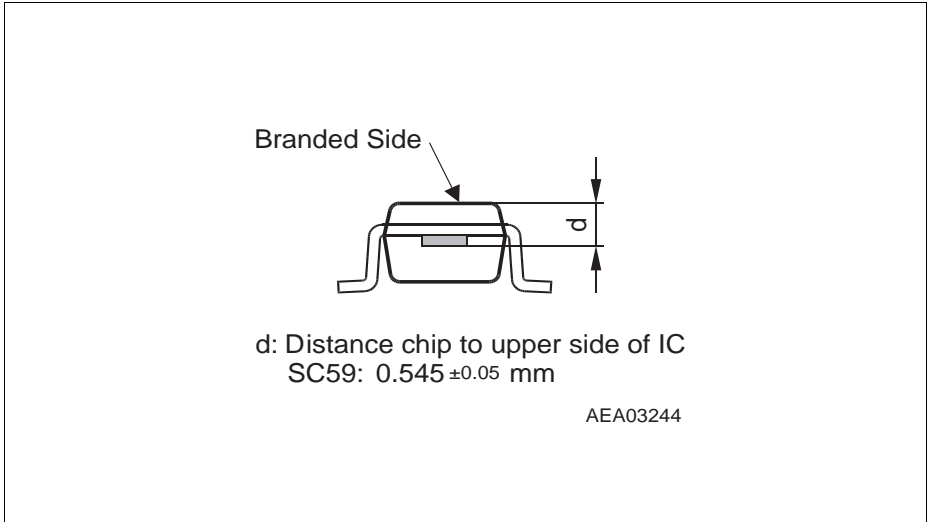


Figure 6 Distance Chip SC59 to Upper Side of IC

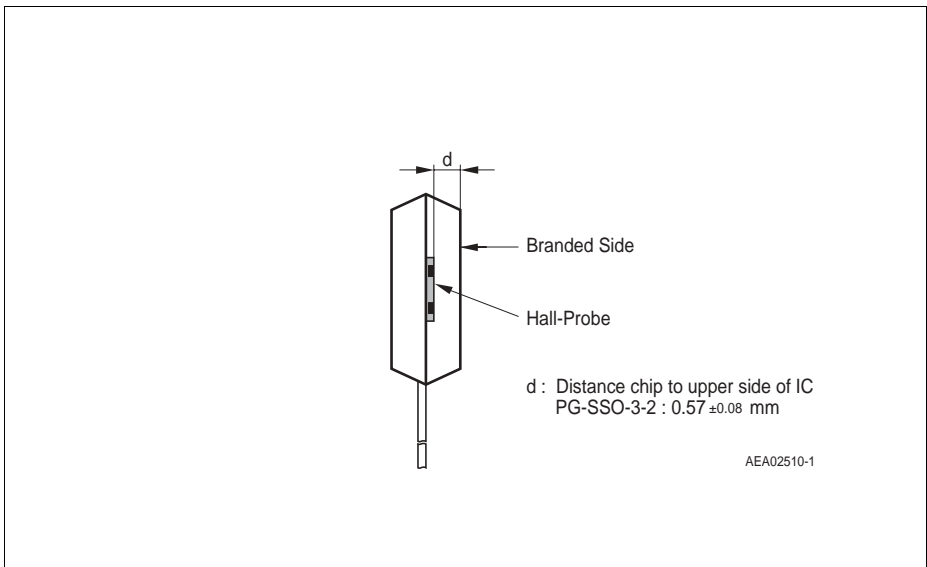


Figure 7 Distance Chip PG-SSO-3-2 to Upper Side of IC

7.3 Package Outlines

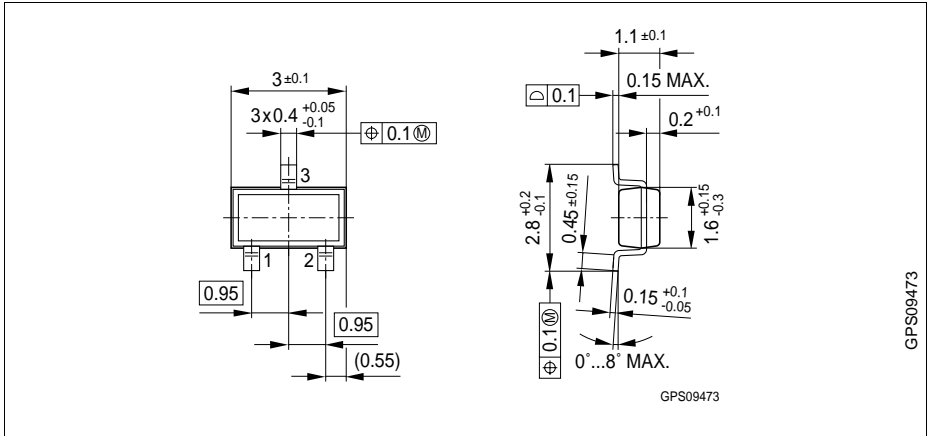


Figure 8 SC59

PCB Footprint for SC59

The following picture shows a recommendation for the PCB layout.

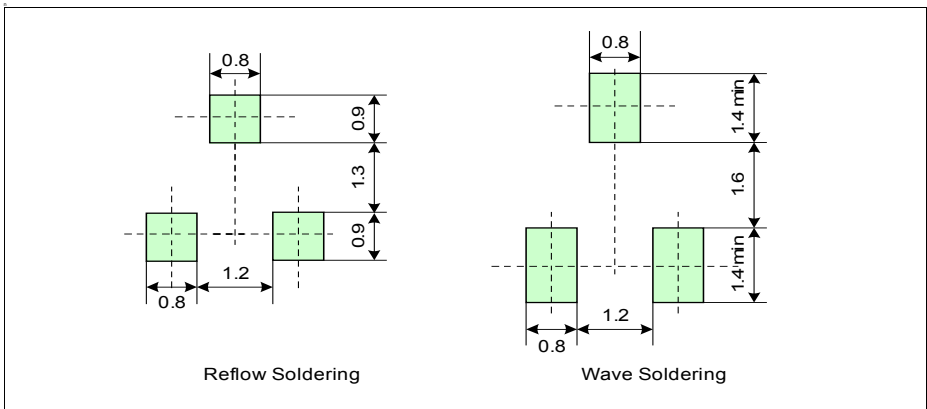


Figure 9 Footprint SC59 (SOT23 compatible)

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